

Notice of References Cited

Application/Control No.

10/060,156

Applicant(s)/Patent Under
Reexamination
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Examiner

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Art Unit

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NON-PATENT DOCUMENTS

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	V	M. R. Frerichs, "PRECISE EXTRACTION OF ULTRA DEEP SUBMISSION INTERCONNECT PARASITIC WITH PARAMETERIZED 3D-MODELING," IEEE, 2/2/2001, PP. 50-55.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.